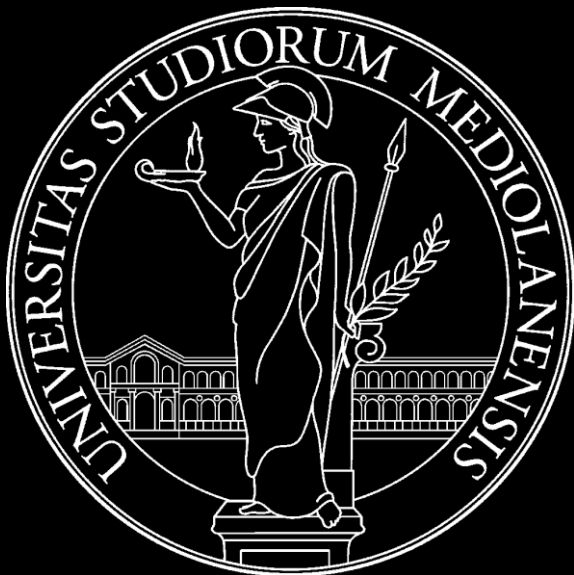


TOWARDS THE REALIZATION OF A COAXIAL AND SEGMENTED DETECTOR FOR GAMMA SPECTROSCOPY EXPERIMENTS



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N3G collaboration

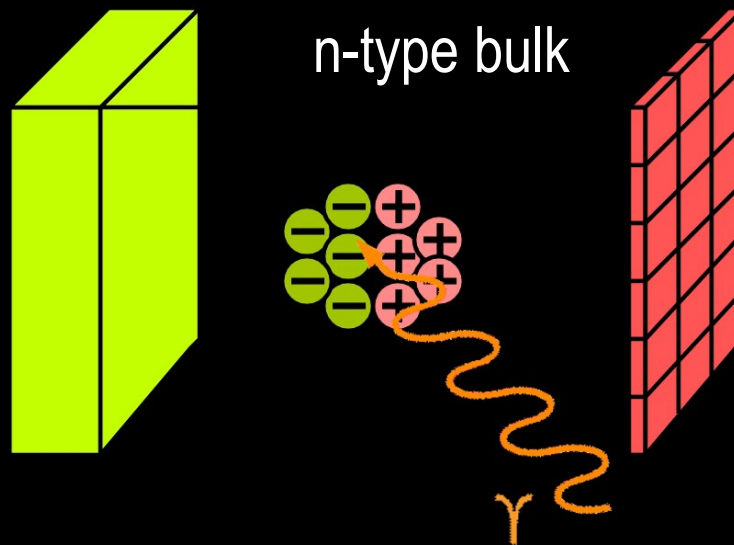


Istituto Nazionale di Fisica Nucleare

STATE OF THE ART HPGE DETECTORS

n+ contact:
electrons collection

diffusion of lithium:
thick layer that can not
be segmented



p+ segmented contact:
holes collection

ion implantation of boron

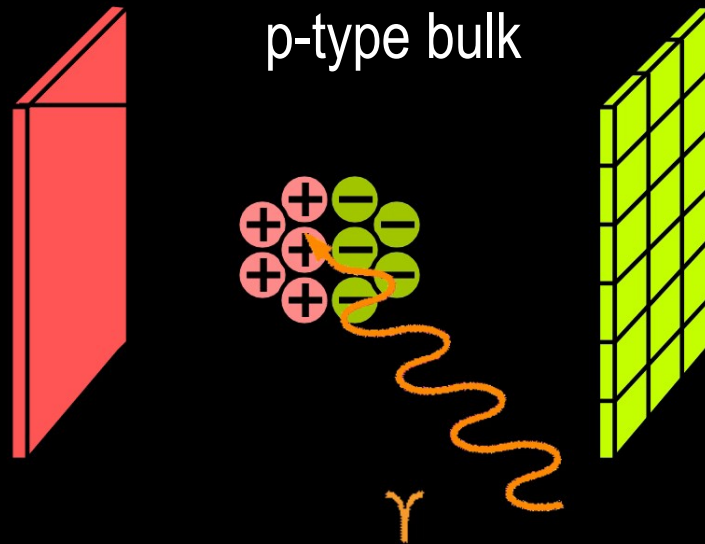
- Segmentation of the p+ contact: tracking analysis with holes signals
- Holes are much more subjected to trapping induced by neutron damage than electrons



THE N3G HPGE DETECTOR

p+ contact:
holes collection

ion implantation of boron



n+ segmented contact:
electrons collection

PLM based doping

- PLM – Pulsed Laser Melting – technology: **segmentation of the n+ contact** (100 nm-300 nm thick)
- Tracking analysis with electrons signals: **resolution improvements**



WHAT DO WE NEED TO MAKE THE DTECTOR ?

High-Purity Germanium (HPGe)

Advanced Photolithography

Reliable Doping-Technology (PLM)

Electronics

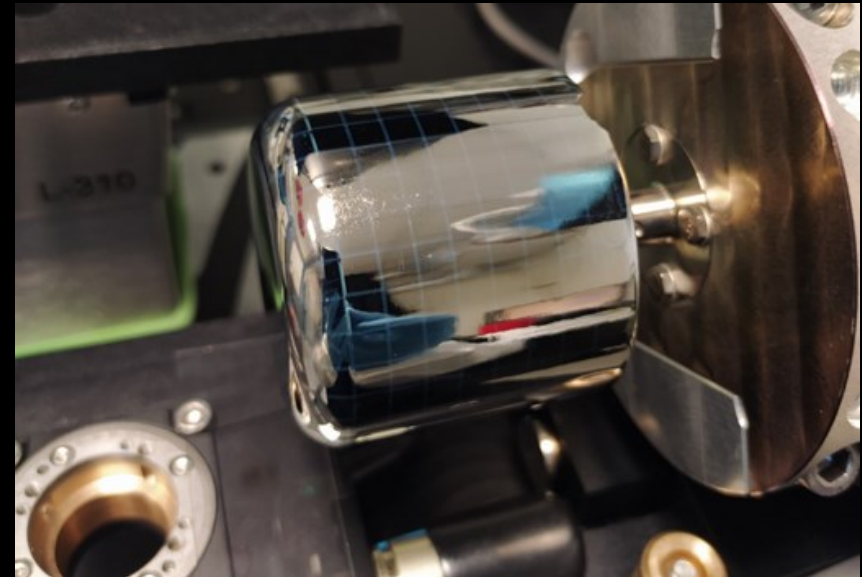
Mechanical Developments

People (with different skills)



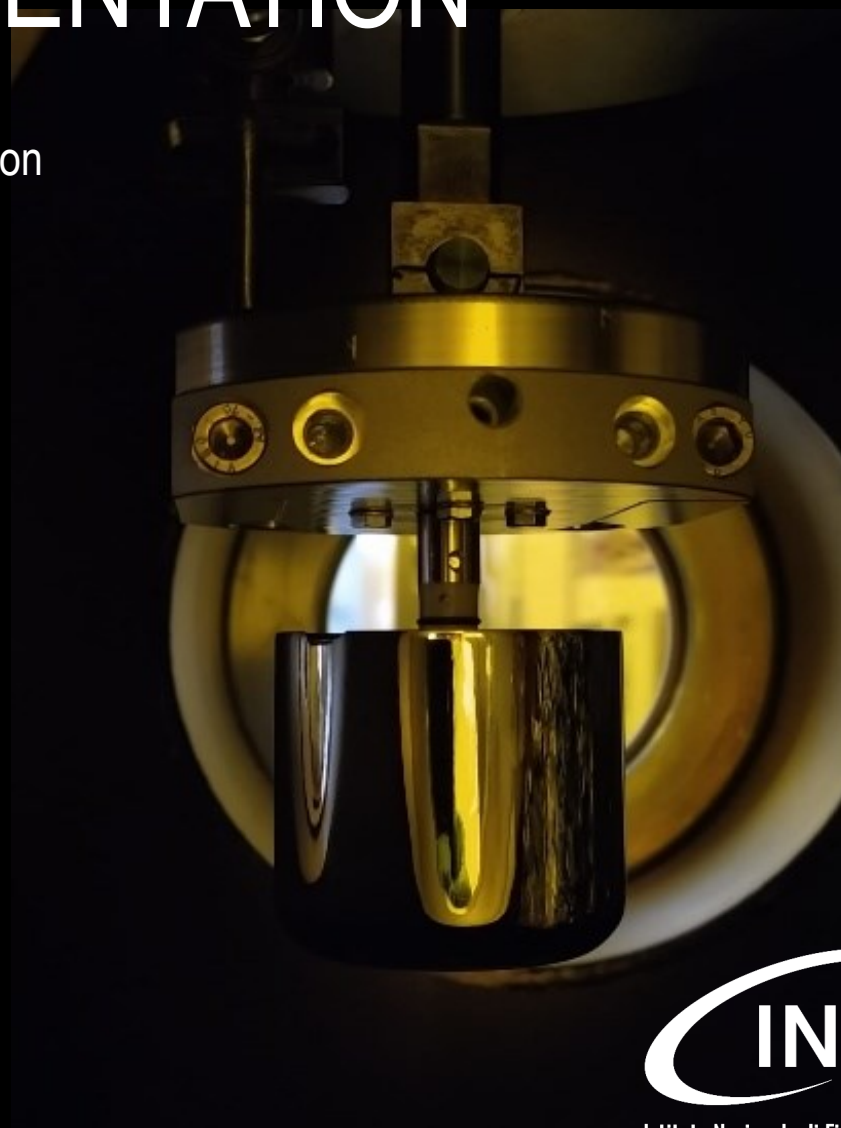
PULSED LASER MELTING TECHNOLOGY

- The HPGE crystal is lapped and etched with acid solution (3 : 1) HNO₃ : HF
- Sputtering deposition or evaporation of a thin (2 nm – 20 nm) pure layer of dopant on Ge
- Followed by cycles of Pulsed Laser Melting (spatial and temporal control)
- Diffusion of high dopant concentrations ($3 \times 10^{20} \text{ cm}^{-3}$) into the melted Ge subsurface layer
- Fast epitaxial regrowth
- Junction depth on the order of 100 nm – 300 nm



PHOTOLITHOGRAPHY SEGMENTATION

- Gold deposition (<100 nm) by RF Magnetron Sputtering on the n+ junction
- Photoresist deposition (<1 μm) and soft bake
- UV irradiation
- Irradiated photoresist removal
- Soft bake to harden the unremoved photoresist on gold layer
- Gold etching to remove gold between segments
- Hot acetone bath to remove the photoresist



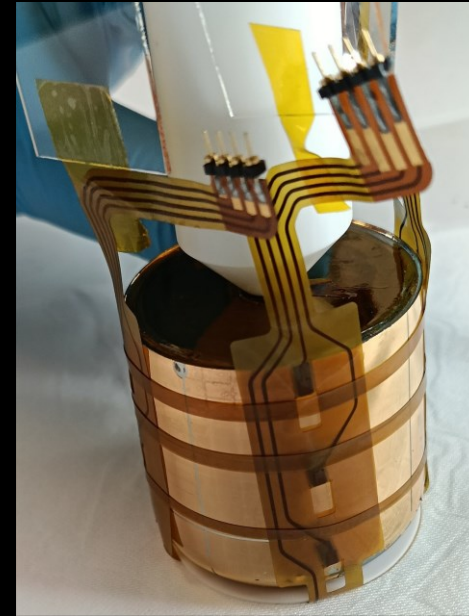
ETCHING & PASSIVATION...*the detector is almost ready*

- The diode is etched with (3 : 1) HNO_3 : HF (<10 s) to remove the junction diffusion on the gaps...gold is not chemically attacked by the solution
- The p+ contact and the back surface are protected with Kapton
- Segmented detector methanol passivation:
 - Chemical barrier for external agents (humidity, condensable vapour)
 - Electrical barrier which isolates contacts/junctions or segments from one another



ELECTRICAL CONNECTIONS

- Flower-shaped flexible PCB (Printed Circuit Board) to be wrapped around the detector
- Good electrical contact, even at cryogenic temperatures
- No damage to the detector surface...damages would increase the detector leakage current



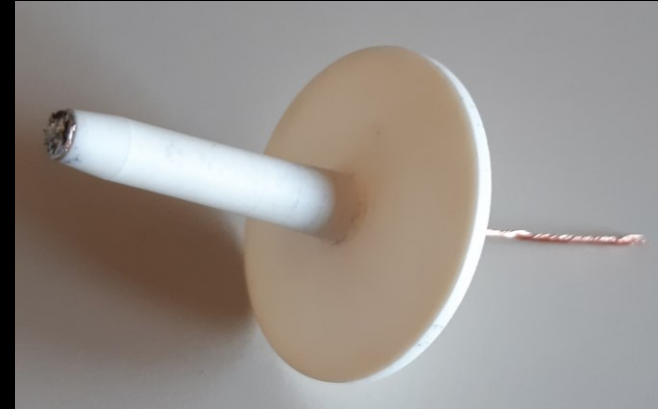
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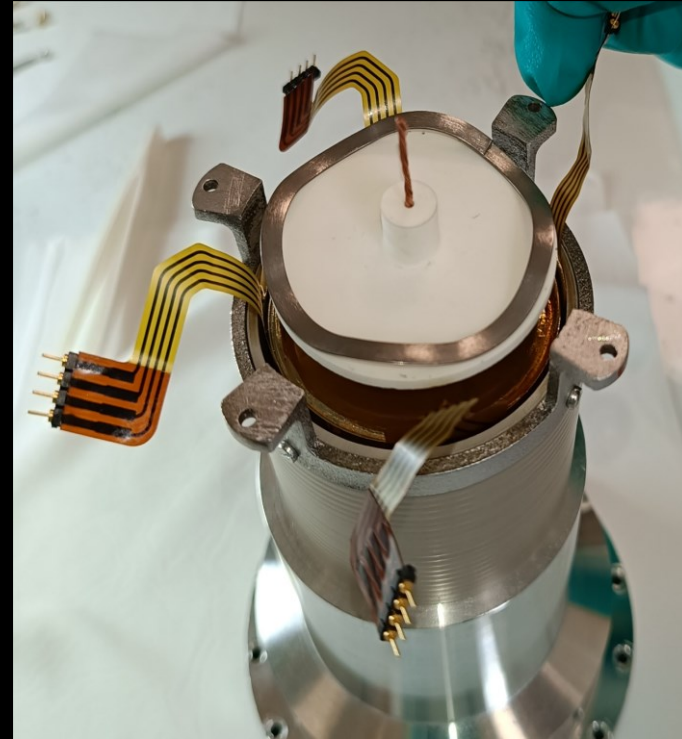
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DETECTOR CASE

- The detector is located on an insulated conical body made of alumina
 - The cone prevents the detector passivated surface from touching the other mechanical components of the canister
- The detector position is kept through a mechanical system made of:
 - PEEK (PolyEther-Ether-Ketone) case
 - Spring-holder
 - Single-wave spring

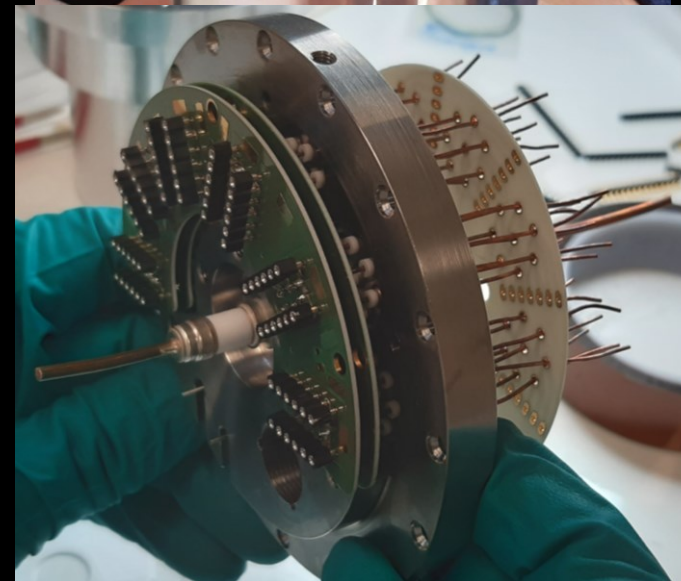
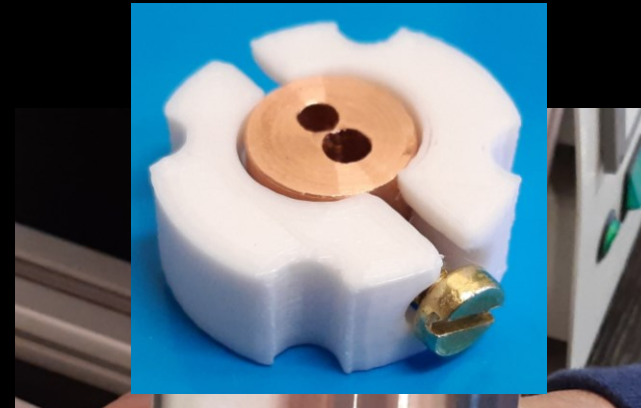


DETECTOR CASE: ASSEMBLY SEQUENCE

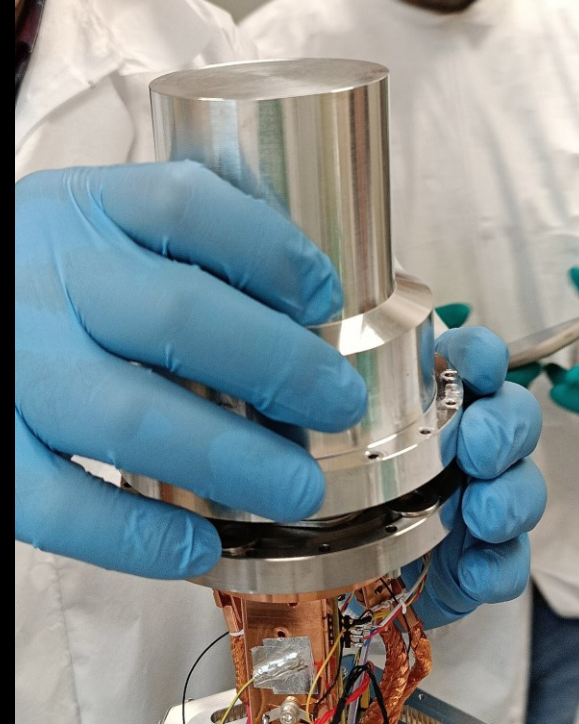
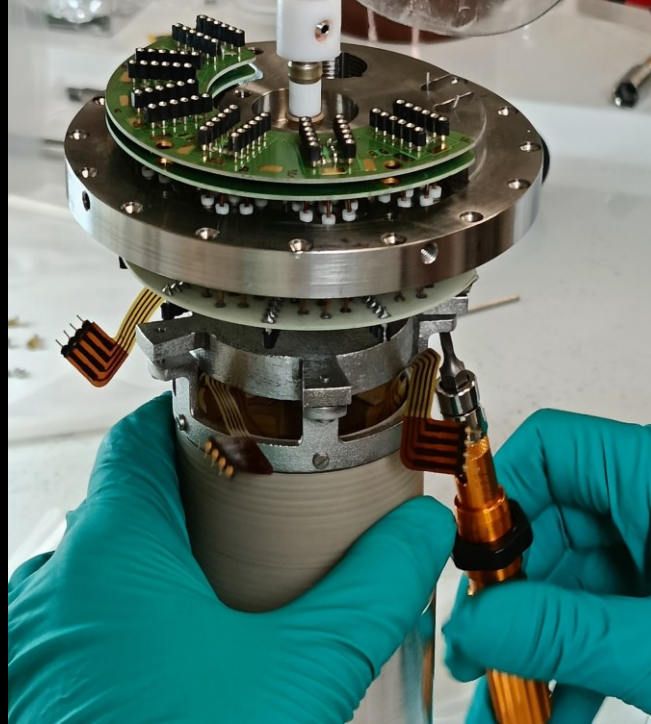


DETECTOR CANISTER

- The detector with its PEEK-case is housed inside a vacuum-tight canister
- The canister consists of an aluminum chamber closed at the bottom by a specifically designed flange
- The flange is equipped with six feedthrough connectors for signals, a high-voltage rod and a vacuum inlet
 - The high-voltage rod must be connected to the cable coming from the alumina conical body
 - Signals are distributed to the feedthrough connectors by means of a rigid PCB

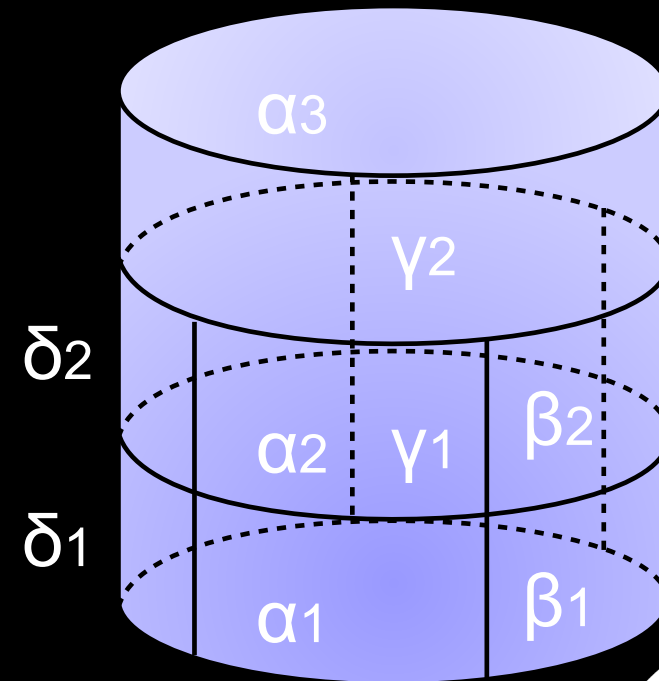


DETECTOR CANISTER: ASSEMBLY SEQUENCE



ROOM TEMPERATURE TEST

- Germanium behaves like a conductor at room temperature...
- Electrical continuity between segments and high-voltage rod → the flexible PCB ensures a good electrical connection to the detector electrodes
- Electrical resistance between adjacent segments:
 - 50 Ω between isolated segments
 - 15 Ω between shorts
 - Upper segments not isolated because of accidental gold removal during the etching procedure

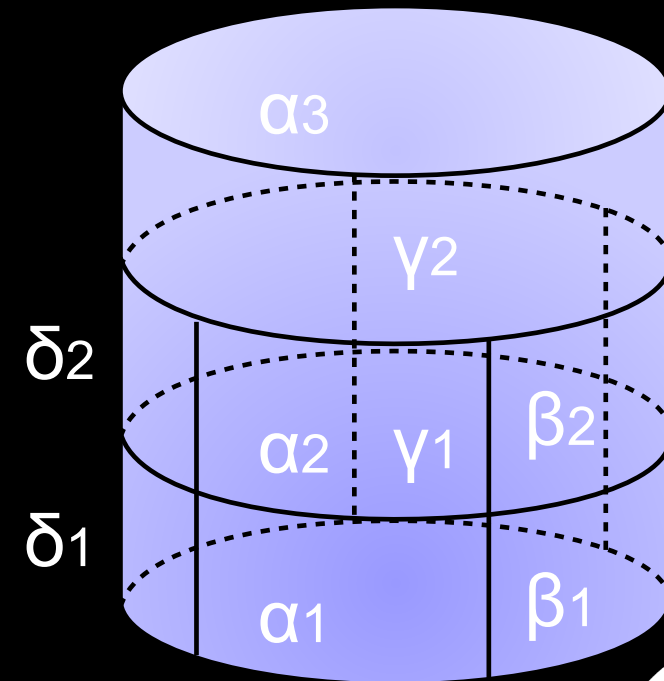


CRYOGENIC TEMPERATURE TEST

- Current-Voltage curves: by varying the voltage applied to the inner contact, the leakage current is extracted segment by segment using a precision ammeter
- alpha 3 high leakage current: accidental gold removal
- alpha1, beta1, gamma1,delta1 high leakage currents: gold on passivation
- Promising results obtained on the central segments

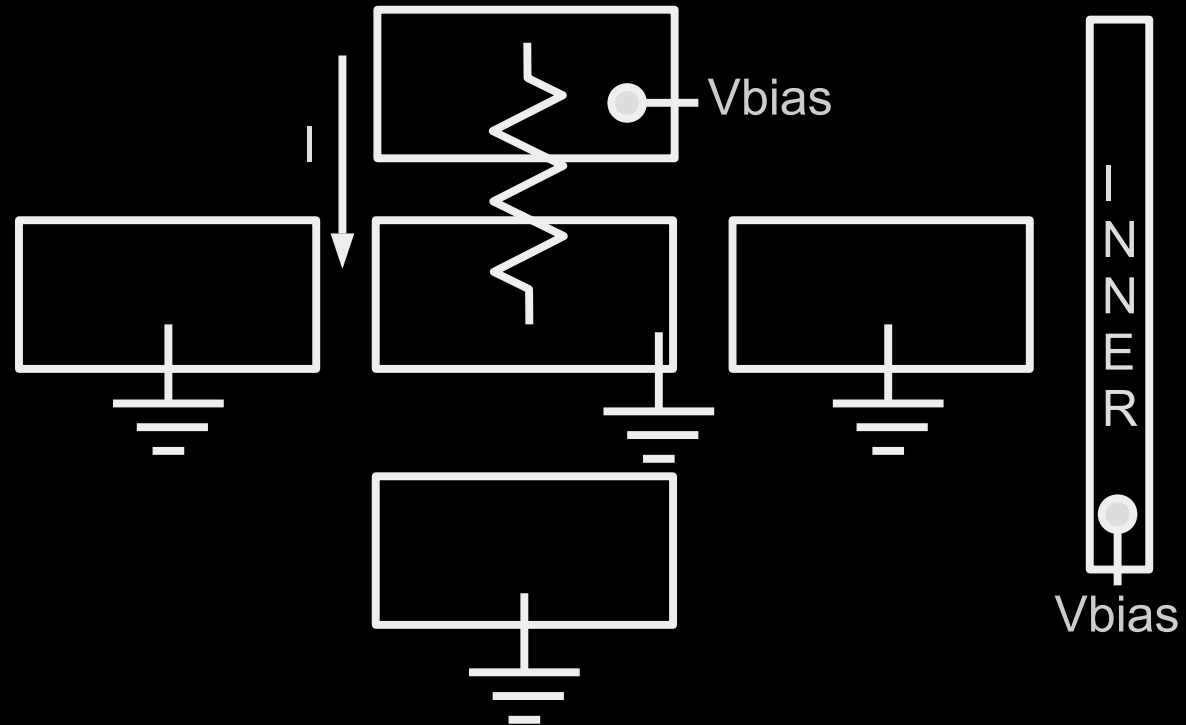


**THE ELECTRICAL CONNECTIONS BASED
ON FLEXIBLE PCBs EFFECTIVLY WORK**



CRYOGENIC TEMPERATURE TEST

- Electrical Resistance Measurements
- Resistance is obtained by applying the Ohm's law, knowing the voltage difference between segments and measuring the current through them
- Resistance between adjacent segments on the order of several T Ω



CONCLUSIONS

- The PLM doping technology has been successfully applied to coaxial detectors
- Lithography on coaxial detectors has been improved
- The flexible PCB has been demonstrated a good way to contact the detector electrodes
- Functional mechanics to contain and protect the detector

